

Search Notes

Application/Control No.

10/644,996

Examiner

Pierre-Louis Desir

Applicant(s)/Patent under
Reexamination

CHUN, CHANG-HYEN

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
455	442	2/21/2007	PD
455	436	2/21/2007	PD
455	522	2/21/2007	PD
455	434	2/21/2007	PD
370	352	2/21/2007	PD

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	2/21/2007	PD

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner